

Search Notes

Application/Control No.

10/741,824

Examiner

John M. Parker

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2823

SEARCHED

Class	Subclass	Date	Examiner
438	652,687	4/13/2006	JMP
438	618	4/13/2006	JMP
257	750,751	4/13/2006	JMP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search attached	4/15/2006	JMP